



Sheet 1 of 1

Form PTO-1449 (Rev. 8-83)	U.S. Department of Commerce Patent and Trademark Office	Atty. Docket No.: 0756-945	Serial No.: 08/169,127
INFORMATION DISCLOSURE STATEMENT		Applicant: Hisato SHINOHARA et al.	
(Use several sheets if necessary)		Filing Date: December 20, 1993	Group: 1112

U.S. PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation
							Yes
							No

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw Line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



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Examiner Initial		Document Number				Date	Name	Class	Subclass	Filing Date (if appropriate)			
		4	1	8	1	5	6	3	1980 Jun	Miyaka et al.	427	53.1	
		4	2	9	2	0	9	2	1981 Sept	Hanak	427	53.1	
		4	4	1	3	0	2	0	1983 Nov	McKee et al.	427	53.1	
		4	6	8	0	8	5	5	1987 July	Yamazaki et al.	156	643	20 11/1
		4	7	1	3	5	1	8	1987 June	Yamazaki et al.	427	53.1	
		4	7	5	3	8	5	5	1988 July	Haluska et al.	427	58	12/4/86
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		Document Number				Date	Country	Class	Subclass	Translation Yes No			
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				Filing Date: December 20, 1993		Group Art Unit: 1762	
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